

**Search Notes**

Application/Control No.

10/668,665

Examiner

Leigh C. Maier

Applicant(s)/Patent under  
Reexamination

YVIN ET AL.

Art Unit

1623

**SEARCHED**

Class	Subclass	Date	Examiner
514	54	10/14/2005	LCM

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
-STN text search (transcript attached)	10/4/2005	LCM
-EAST (transcript attached)	10/14/2005	LCM